

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

ADAN

Atty. Ref.: 1035-504

Serial No. Unknown

TC/A.U.:

Filed: April 2, 2004

Examiner:

For: INTEGRATED CIRCUIT

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April 2, 2004

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

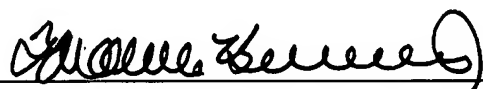
INFORMATION DISCLOSURE STATEMENT

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO-1449, a copy of each non-U.S. patent being enclosed. This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

The Examiner is requested to initial the attached form PTO-1449 and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Respectfully submitted,

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**INFORMATION DISCLOSURE
CITATION**

ATTY. DOCKET NO.

SERIAL NO.

1035-504

Unknown

APPLICANT

ADAN

(Use several sheets if necessary)

FILING DATE

TC/A.U.

April 2, 2004

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,307,252	10/2001	KNOEDL			

FOREIGN PATENT DOCUMENTS

DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
10-256250	09/1998	JAPAN			PARTIAL

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

	"On-Chip Spiral Inductors with Patterned Ground Shields for Si-Based RF IC's" [C. Patrick Yue et al., IEEE Journal of Solid-State Circuits, vol. 33, No.5, pp. 743-752, May 1998]
	"Deep Trench Guard Technology to Suppress Coupling between Inductors in Silicon RF ICs" [Cheon Soo Kimm et al., 2001 IEEE]
	"Future EMC Trends in PC Board Design" [Bruce Gabrielson, EMC EXPO 1996, June 16 to 19, 1996]

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.